



# ALD/CVD High K and Metal Precursors

For Semiconductor Applications

## TECHCET

### A Critical Materials Report

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## RESEARCH METHODOLOGY

TEHCET employs subject matter experts having first-hand experience within the industries, which they analyze. Most of TEHCET's analysts have over 25 years of direct and relevant experience in their field. Our analysts survey the commercial and technical staff of IC manufacturers and their suppliers, and conduct extensive research of literature and commerce statistics to ascertain the current and future market environment and global supply risks. Combining this data with TEHCET's proprietary, quantitative wafer forecast results in a viable long-term market forecast for a variety of process materials.

Readers Note: This report represents the interpretation and analysis of information generally available to the public or released by responsible agencies or individuals. Data was obtained from sources considered reliable. However, accuracy or completeness is not guaranteed.

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